

## INTERNATIONAL SEARCH REPORT

Inter Application No  
PCT/IB2004/052753

A. CLASSIFICATION OF SUBJECT MATTER  
IPC 7 H01L21/265 H01L21/20

According to International Patent Classification (IPC) or to both national classification and IPC

## B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)  
IPC 7 H01L

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

EPO-Internal, INSPEC

## C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	MATSUNAGA Y ET AL: "Effect of surface treatment during Ge<+>/B<+> two step ion implantation" ION IMPLANTATION TECHNOLOGY PROCEEDINGS, 1998 INTERNATIONAL CONFERENCE ON KYOTO, JAPAN 22-26 JUNE 1998, PISCATAWAY, NJ, USA, IEEE, US, vol. 1, 22 June 1998 (1998-06-22), pages 668-671, XP010362035 ISBN: 0-7803-4538-X the whole document	1-10
X	US 6 165 876 A (YAMAZAKI ET AL) 26 December 2000 (2000-12-26) emdodiments; figure 7 ----- -/--	8-10

☒ Further documents are listed in the continuation of box C.

☒ Patent family members are listed in annex.

## \* Special categories of cited documents :

"A" document defining the general state of the art which is not considered to be of particular relevance

"E" earlier document but published on or after the international filing date

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"O" document referring to an oral disclosure, use, exhibition or other means

"P" document published prior to the international filing date but later than the priority date claimed

"T" later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention

"X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone

"Y" document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art.

"&" document member of the same patent family

Date of the actual completion of the international search

13 July 2005

Date of mailing of the international search report

27/07/2005

Name and mailing address of the ISA

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Intern

Application No

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## C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	NAEM A A ET AL: "FORMATION OF SHALLOW N+P JUNCTIONS" JOURNAL OF APPLIED PHYSICS, AMERICAN INSTITUTE OF PHYSICS. NEW YORK, US, vol. 62, no. 2, 15 July 1987 (1987-07-15), pages 569-575, XP000819591 ISSN: 0021-8979 abstract; II. EXPERIMENTAL PROCEDURE -----	1-10
A	US 2003/207542 A1 (CHIDAMBARAM P.R ET AL) 6 November 2003 (2003-11-06) paragraphs '0043! - '0046!; claims 1-8; figures 5-8 -----	1-10
A	US 5 254 484 A (HEFNER ET AL) 19 October 1993 (1993-10-19) claim 1 -----	1-10
A	US 4 683 645 A (NAGUIB ET AL) 4 August 1987 (1987-08-04) claims -----	1-10

# INTERNATIONAL SEARCH REPORT

Information on patent family members

Interr

I Application No

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Patent document cited in search report		Publication date	Patent family member(s)	Publication date
US 6165876	A	26-12-2000	JP 8204208 A JP 3512550 B2 JP 8274344 A	09-08-1996 29-03-2004 18-10-1996
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